

FAST - (09-740634.wsp.1)

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(286) 324/763.ccls.
(44) 324/763.ccls. and multiplexer
(4) "1088239"
(7872) schmid
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(1) "19826835"
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(47) ((externally same accessible).ti,ab,clm.) and 324/5
(41) 3849872.URPN.
(12) 3801910.URPN.
(1) "3539876".PN.
(3) ("3539876" | "3633268" | "3634731").PN.
(0) time near controlled same multiplex\$ same integrated
(7) multiplex\$ same integrated near circuit
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(104) time same multiplex\$
(16) time same multiplexing
(0) time with multiplex\$ same integrated near circuit

		Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval C	Inver
1	<input checked="" type="checkbox"/>	US 5321277 A	19940614	8	Multi-chip module testing	257/48	257/390; 365/200;		Sparks, Stev al.
2	<input checked="" type="checkbox"/>	US 5097205 A	19920317	8	IC chip test circuit for high frequency integrated circuits	324/763	324/73.1; 327/564		Toyoda, Nobu
3	<input checked="" type="checkbox"/>	US 3801910 A	19740402	6	EXTERNALLY ACCESSING MECHANICAL DIFFICULT TO ACCESS CIRCUIT NODES USING PHOTO-RESPONSIVE CONDUCTORS IN INTEGRATED	324/752	257/461		Quinn, Huber
4	<input checked="" type="checkbox"/>	US 3849872 A	19741126	6	CONTACTING INTEGRATED CIRCUIT CHIP TERMINAL THROUGH THE WAFER KERF	438/17	257/734; 324/158.1;		Hubacher, Et
5	<input checked="" type="checkbox"/>	US 4982403 A	19910101	8	Electrical circuit testing device and circuit comprising the said device	714/732			Du Chene, Ar al.
6	<input checked="" type="checkbox"/>	US 5895978 A	19990420	8	High density signal multiplexing interposer	257/786	257/678; 257/698;		Palagonia, A Michael
7	<input checked="" type="checkbox"/>	US 6127729 A	20001003	17	Semiconductor chip with corner electrode terminals and detecting wiring for defect inspection	257/736	257/208; 257/210;		Fukuda, Kazu
8	<input checked="" type="checkbox"/>	US 4908576 A	19900313	45	System for printed circuit board testing	714/726	324/73.1; 324/754;		Jackson, Dar
9	<input checked="" type="checkbox"/>	US 6448783 B1	20020910	17	Method of inspecting semiconductor chip with projecting electrodes for defects	324/537	324/765		Fukuda, Kazu
10	<input checked="" type="checkbox"/>	US 6184569 B1	20010206	14	Semiconductor chip inspection structures	257/620	257/48; 257/E23.151		Fukuda, Kazu
11	<input checked="" type="checkbox"/>	US 6362523 B1	20020326	8	Semiconductor device	257/723	257/528; 257/E23.142;		Fukuda, Kazu
12	<input checked="" type="checkbox"/>	US 4724379 A	19880209	7	Relay multiplexing for circuit testers	307/115	324/158.1; 714/734		Hoffman, Mar
13	<input checked="" type="checkbox"/>	EP 533589 A1	19930324	17	A semiconductor device.		257/203; 257/786;	257/786	OGAWA, JUNJI
14	<input checked="" type="checkbox"/>	US 5418470 A	19950523	6	Analog multi-channel probe system	324/763	324/158.1; 714/733		Dagostino, T et al.
15	<input checked="" type="checkbox"/>	US 5712858 A	19980127	12	Test methodology for exceeding tester pin count for an asic device	714/724			Godiwala, Ni Dhuroobhai e

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